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**Test methods for structural
parameters of optical fibers—
Optical characteristics**

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Contents

	Page
Introduction	1
1 Scope	1
2 Normative references	1
3 Terms and definitions	2
4 Classification of optical fibers	2
5 Test site conditions	3
6 Test methods of numerical aperture (<i>NA</i>)	3
6.1 Overview of test method	3
6.2 Reference test method	4
6.3 FFP method	5
6.4 Reflection method	9
6.5 Specification information	10
7 Test methods of cut-off wavelength	11
7.1 Types of cut-off wavelength	11
7.2 Overview of test method	11
7.3 Mapping functions	12
7.4 Reference test method	12
7.5 Apparatus	12
7.6 Sampling and specimens	14
7.7 Positioning of specimen in apparatus	14
7.8 Procedure and calculation method	14
7.9 Results	14
7.10 Specification information	15
8 Test methods of mode field diameter (<i>MFD</i>)	15
8.1 General consideration	15
8.2 Reference test method	16
8.3 Apparatus	16
8.4 Sampling and specimens	18
8.5 Procedure	18
8.6 Calculations of <i>MFD</i>	18
8.7 Results	20
8.8 Specification information	21
Annex A (normative) Requirements related to numerical aperture test apparatus used in FFP method and reflection method	22
Annex B (informative) Mapping <i>NA</i> measurement to alternative lengths	29

Annex C (normative)	Product specific default values for NA measurement	30
Annex D (normative)	Requirements specific to cut-off wavelength test Method A — Cable cut-off wavelength (λ_{cc}) using uncabled fiber	31
Annex E (normative)	Requirements specific to cut-off wavelength test Method B — Cable cut-off wavelength (λ_{cc}) using cabled fiber	32
Annex F (normative)	Requirements specific to cut-off wavelength test Method C — Fiber cut-off wavelength (λ_c)	33
Annex G (normative)	Measurement of cut-off wavelength using bend reference technique and calculation procedure	35
Annex H (normative)	Measurement of cut-off wavelength using multimode reference technique and calculation procedure	37
Annex I (normative)	Curve-fitting technique for improved precision of cut-off wavelength test	39
Annex J (normative)	Requirements specific to Method A — Mode field diameter by direct far-field scan	42
Annex K (normative)	Requirements specific to Method B — Mode field diameter by variable aperture in the far field	44
Annex L (normative)	Requirements specific to Method C — Mode field diameter by near-field scan	47
Annex M (normative)	Requirements specific to Method D — Mode field diameter by optical time domain reflectometer (OTDR).....	50
Annex N (informative)	Sample data sets and calculated values	55
Annex JA (informative)	Comparison table between JIS and corresponding International Standards	57

Foreword

This Japanese Industrial Standard has been revised by the Minister of Economy, Trade and Industry through deliberations at the Japanese Industrial Standards Committee as the result of proposal for revision of Japanese Industrial Standard submitted by Optoelectronic Industry and Technology Development Association (OITDA)/Japanese Standards Association (JSA) with a draft being attached, based on the provision of Article 12, paragraph (1) of the Industrial Standardization Act applied *mutatis mutandis* pursuant to the provision of Article 16 of the said Act. This edition replaces the previous edition (**JIS C 6825:2009**), which has been technically revised.

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Test methods for structural parameters of optical fibers—Optical characteristics

Introduction

This Japanese Industrial Standard has been prepared based on **IEC 60793-1-1:2017**, Edition 4, **IEC 60793-1-43:2015**, Edition 2, **IEC 60793-1-44:2011**, Edition 2 and **IEC 60793-1-45:2017**, Edition 2 by incorporating the part corresponding to this Standard without any modifications of the technical contents, but also adding some **JIS** specification contents (classification of optical fiber, standard atmospheric condition and test method for all plastic multimode optical fiber) that are not given in the said corresponding International Standards.

The dotted underlines indicate changes from the corresponding International Standard. A list of modifications with the explanations is given in Annex JA.

1 Scope

This Standard specifies the test methods for structural parameters related to the optical characteristics of optical fibers or jacketed optical fibers of single-mode optical fibers, silica-based multimode optical fibers, multi-component multimode optical fibers, plastic cladding multimode optical fibers, all plastic multimode optical fibers and intraconnection optical fibers (hereafter generically referred to as optical fibers).

NOTE The International Standards corresponding to this Standard and the symbol of degree of correspondence are as follows.

IEC 60793-1-1:2017 *Optical fibres—Part 1-1: Measurement methods and test procedures—General and guidance*

IEC 60793-1-43:2015 *Optical fibres—Part 1-43: Measurement methods and test procedures—Numerical aperture measurement*

IEC 60793-1-44:2011 *Optical fibres—Part 1-44: Measurement methods and test procedures—Cut-off wavelength*

IEC 60793-1-45:2017 *Optical fibres—Part 1-45: Measurement methods and test procedures—Mode field diameter* (overall evaluation: MOD)

In addition, symbols which denote the degree of correspondence in the contents between the relevant International Standards and **JIS** are IDT (identical), MOD (modified), and NEQ (not equivalent) according to **ISO/IEC Guide 21-1**.

2 Normative references

The following standards contain provisions which, through reference in this text, constitute provisions of this Standard. The most recent editions of the standards (including amendments) indicated below shall be applied.

JIS C 6820 *General rules of optical fibers*

NOTE Corresponding International Standards: IEC 60793-1-1 *Optical fibres—Part 1-1: Measurement methods and test procedures—General and guidance* and IEC 60793-2 *Optical fibres—Part 2: Product specifications—General*